

DUNE Optical Test Stand
Setup and First Measurements
At Room Temperature

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Summary

The optical test stand described in earlier presentations has been (it was powered down when not in use over the summer to relieve the cooling system burden)

The tests to be carried out on the components of interest for DUNE cryogenic links (SFP+ modules to start with) have been verified.

Presented here are initial room temperature test results including tests on two categories of devices:

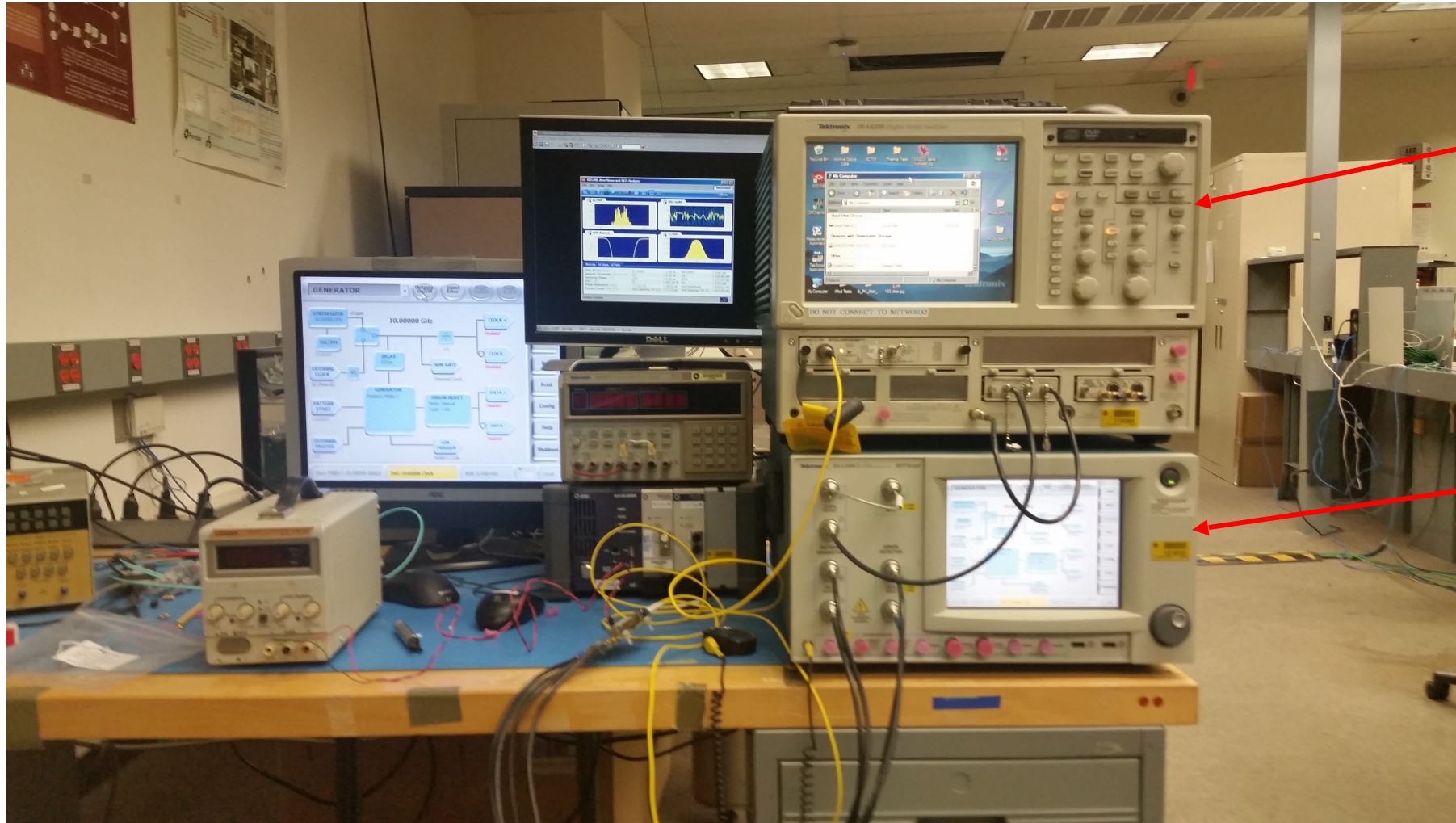
SFP+ TRx devices with Fabry-Perot (F-P) Lasers as transmitters.

SFP+ TRx devices with Distributed FeedBack (DFB) Lasers as transmitters.

In the results presented here, the receiver channel (Rx) of each device was left unpowered and no optical signal was presented to its input. This was done to more accurately characterize the power consumption of the transmitter channel (Tx) only (a figure of merit of importance to DUNE). The SMA connectors on the Rx outputs were terminated with 50 Ohms to ground to help prevent any chatter that might occur.

The test configuration block diagrams have been presented in earlier presentations and are not repeated here.

Key Test Stand Components



Tektronix DSA8200:

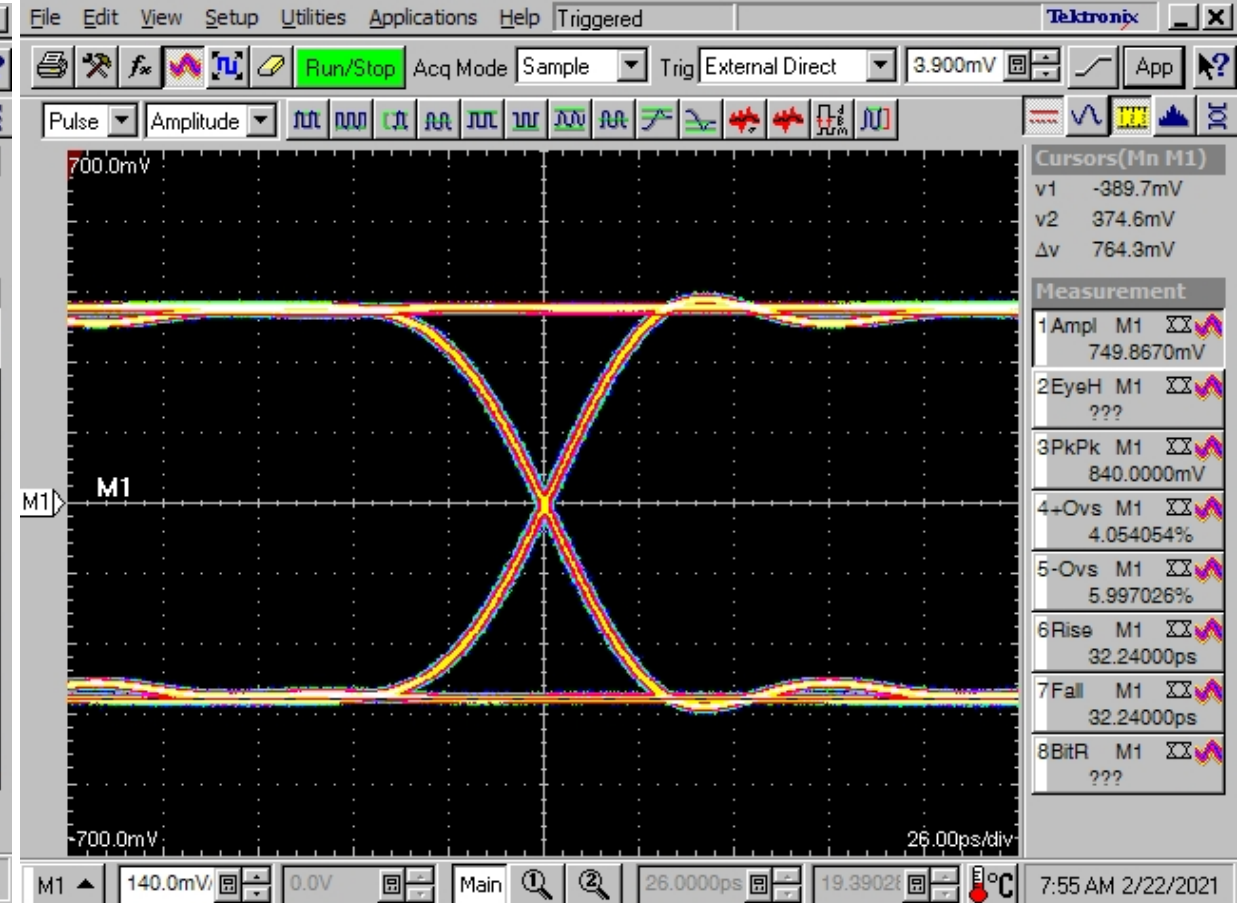
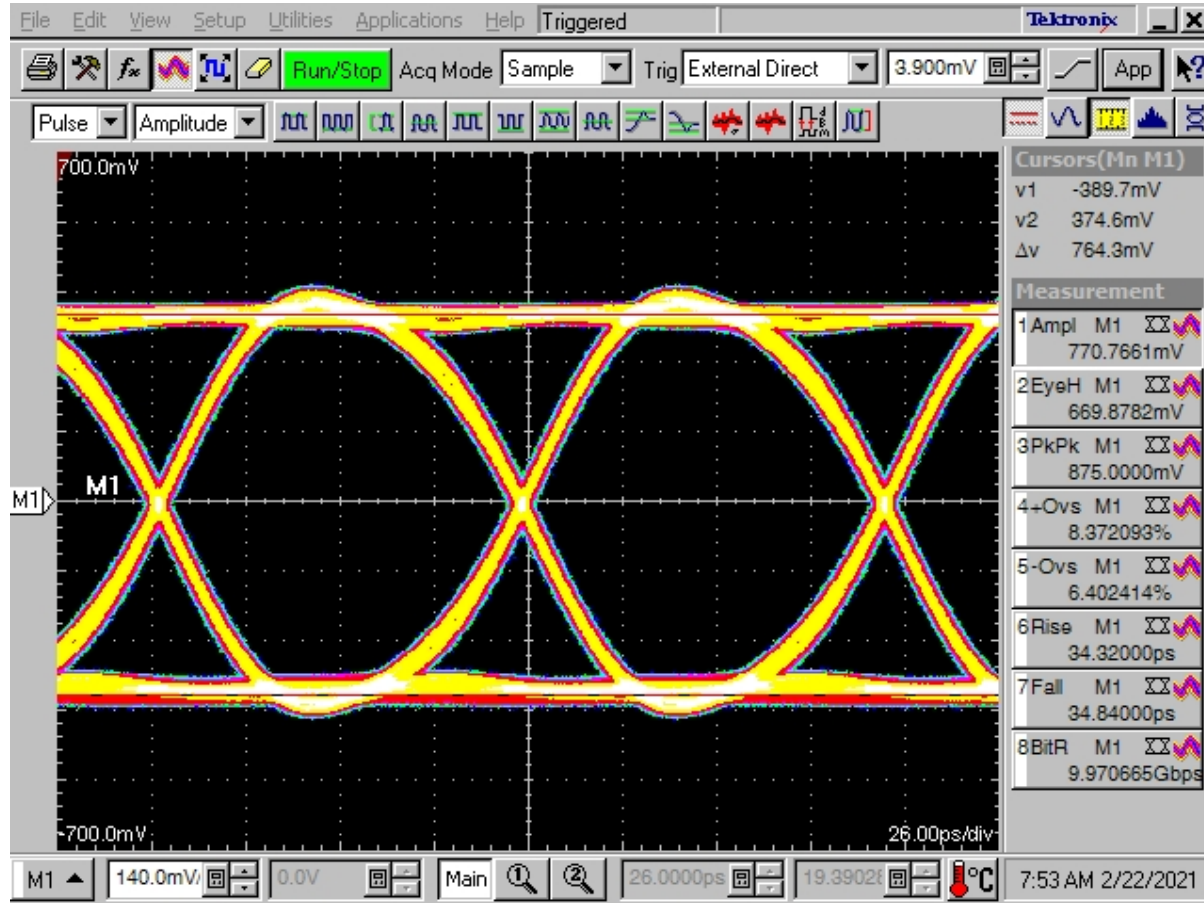
- Optical Sampling
- Electrical Sampling
- Optical Jitter
- Electrical Jitter

Tektronix BSA286CL
BER Tester:

- Electrical Pattern
Generator
- Electrical Error
Checker

BSA286CL Pattern Generator Electrical Eyes

10 Gbps PRBS7 (127 bits); LVDS Levels; AC Coupled



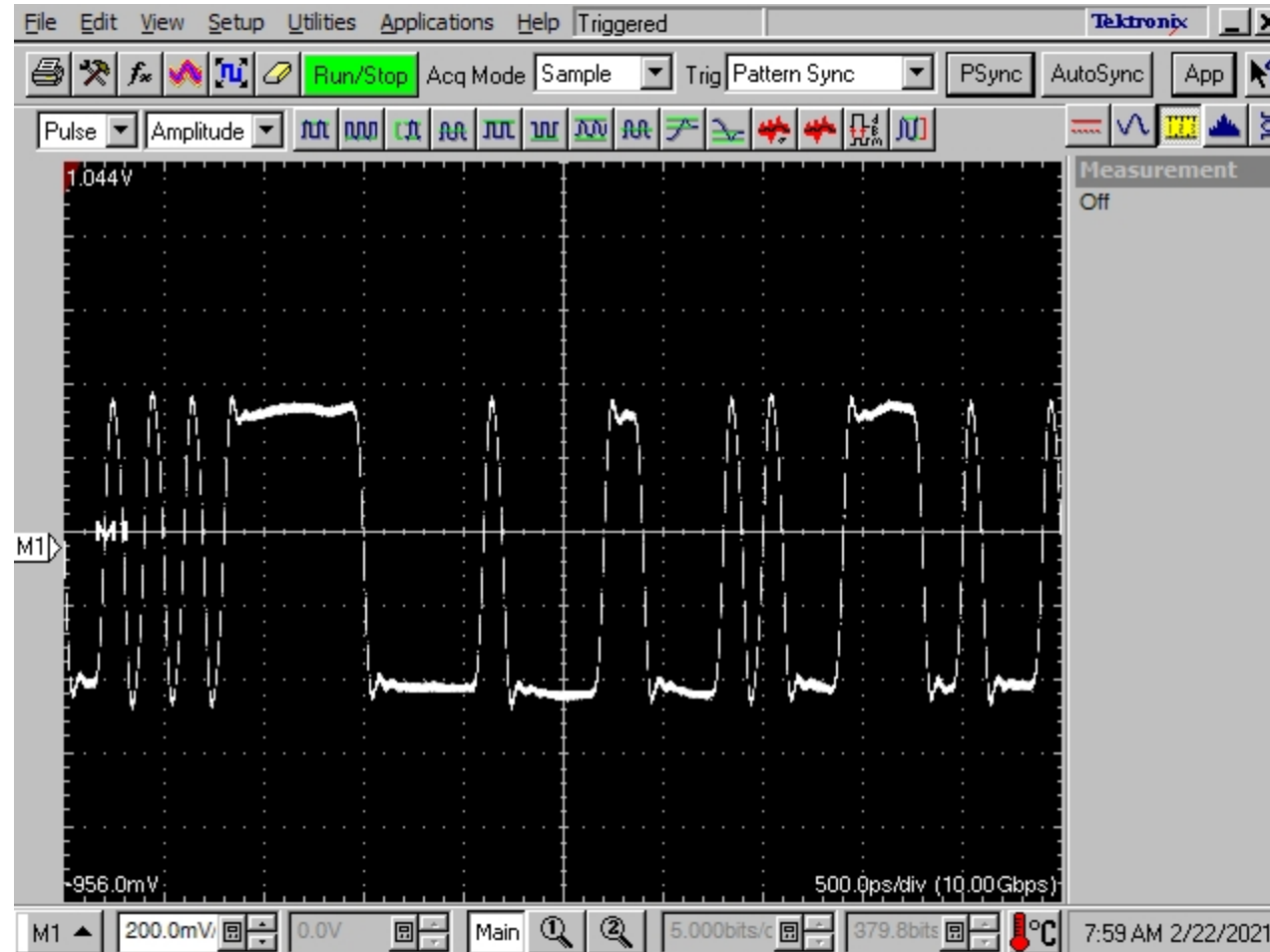
Source Rise Time ($t_{src}(\text{rise})$): 32.2 ps

Data Rate: 10 Gbps

Source Fall Time ($t_{src}(\text{fall})$): 32.2 ps

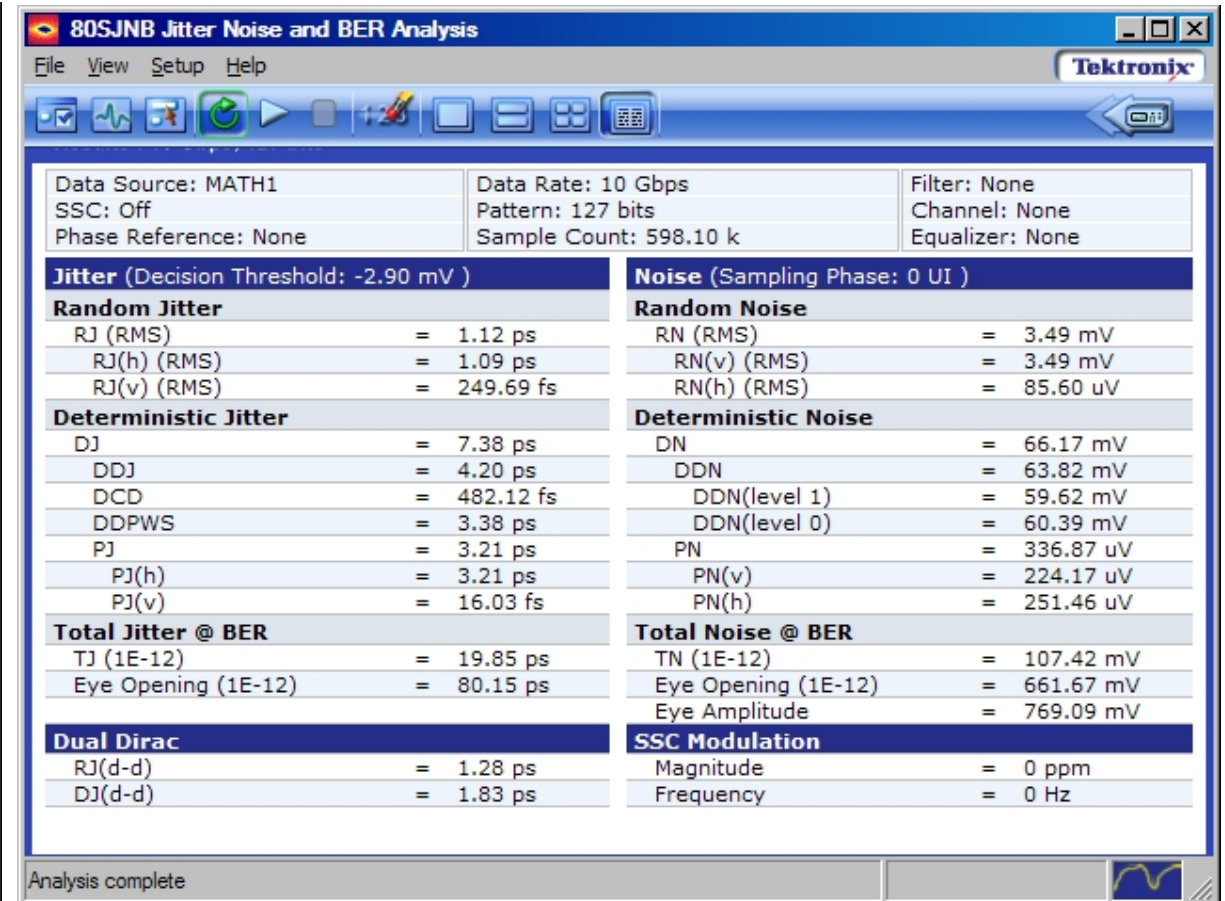
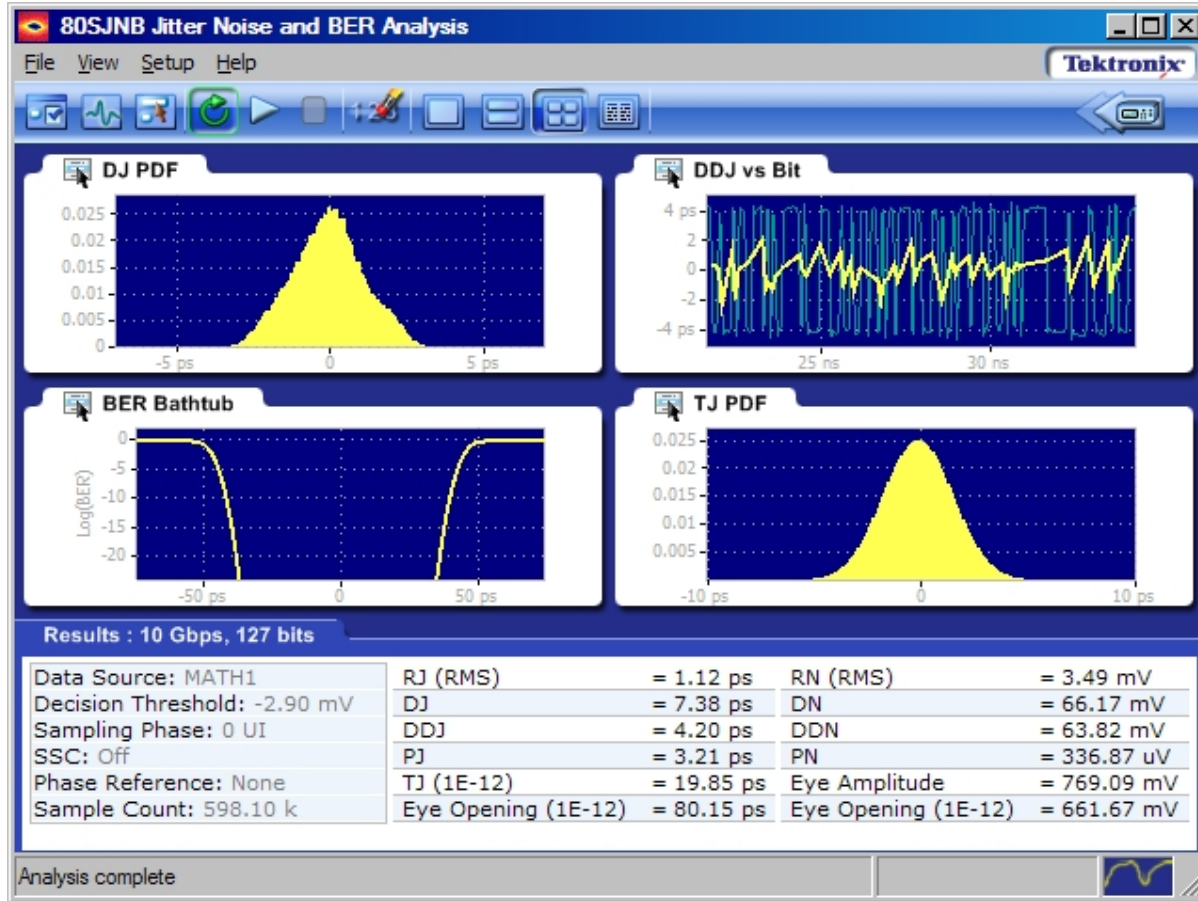
These are the measurements obtained on the source which are needed for compensation to characterize the rise/fall times of the DUT itself.

BSA286CL Pattern Generator 10 Gbps PRBS7 Synchronized Electrical Pattern



This waveform is viewed as a check that the instrument is synchronized with the repeating PRBS pattern (necessary for accurate jitter composition measurements)

BSA286CL Pattern Generator 10 Gbps PRBS7 Electrical Jitter



$$RJ_{src} = 1.12 \text{ ps (RMS)}$$

$$TJ_{src} = 19.85 \text{ ps}$$

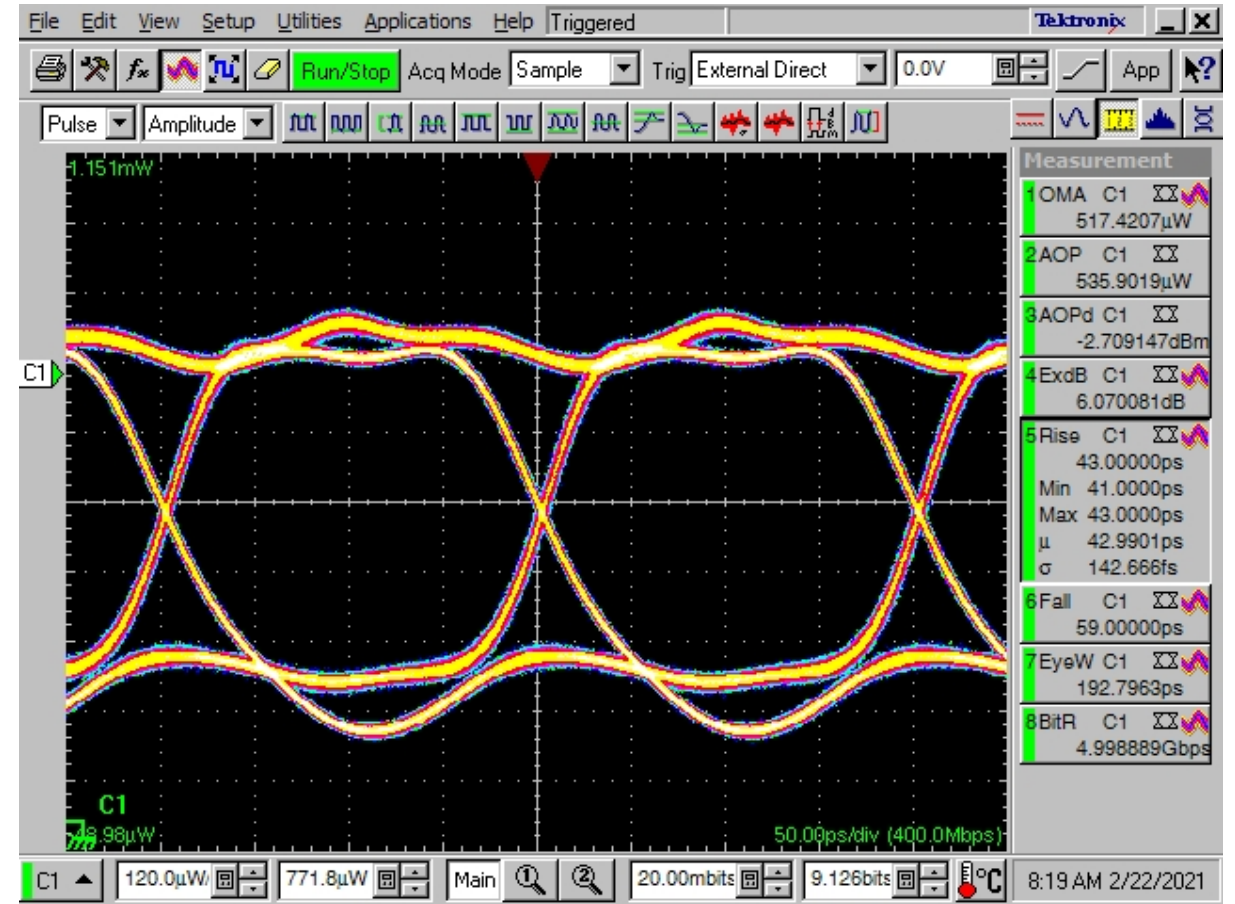
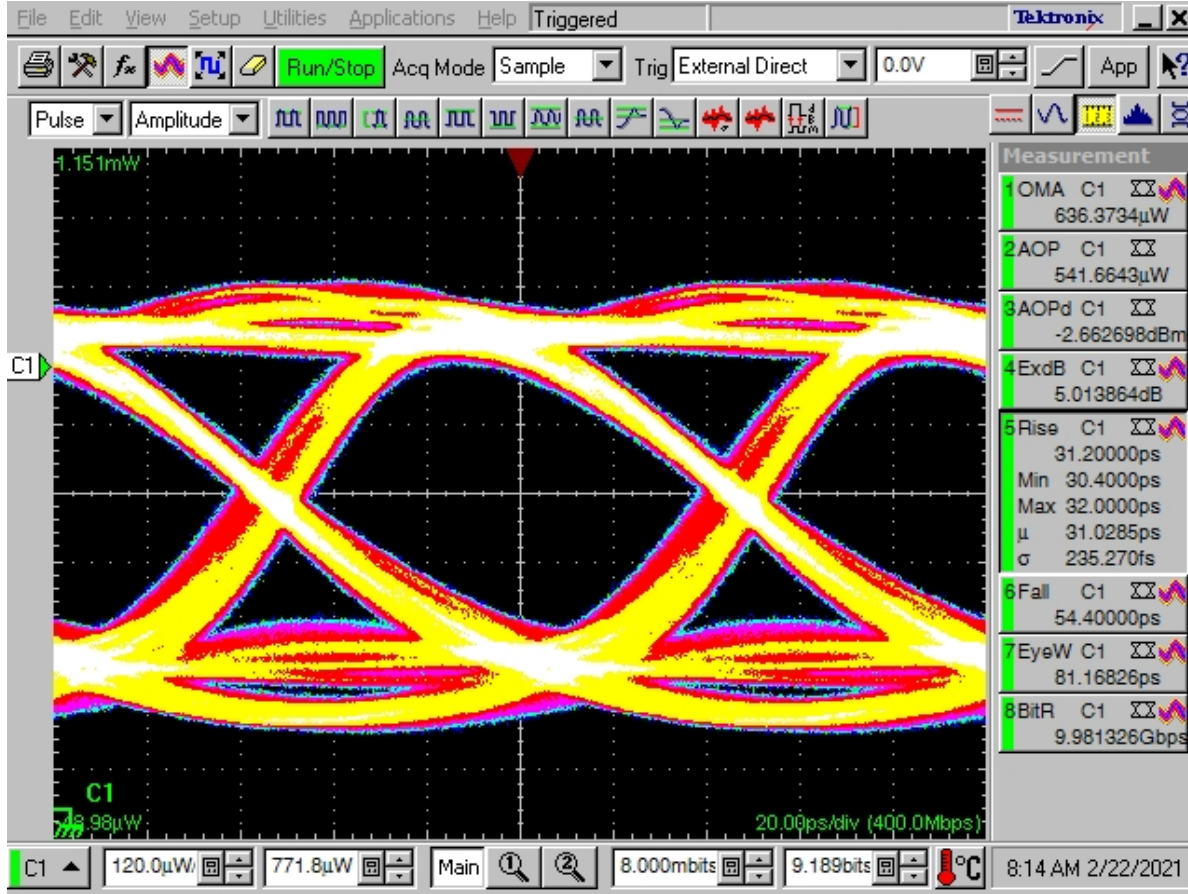
These are the jitter statistics obtained on the source which are needed for compensation to characterize the jitter contribution of the DUT itself.

Fabry-Perot (F-P) Device 1 Optical Eyes

10 Gbps PRBS7 (127 bits)

Average Optical Power: 542 μ W

Optical Modulation Amplitude: 636 μ W



Extinction Ratio: 5.0 dB

Data Rate: 10 Gbps

Measured Rise Time ($t_{meas}(\text{rise})$): 43 ps

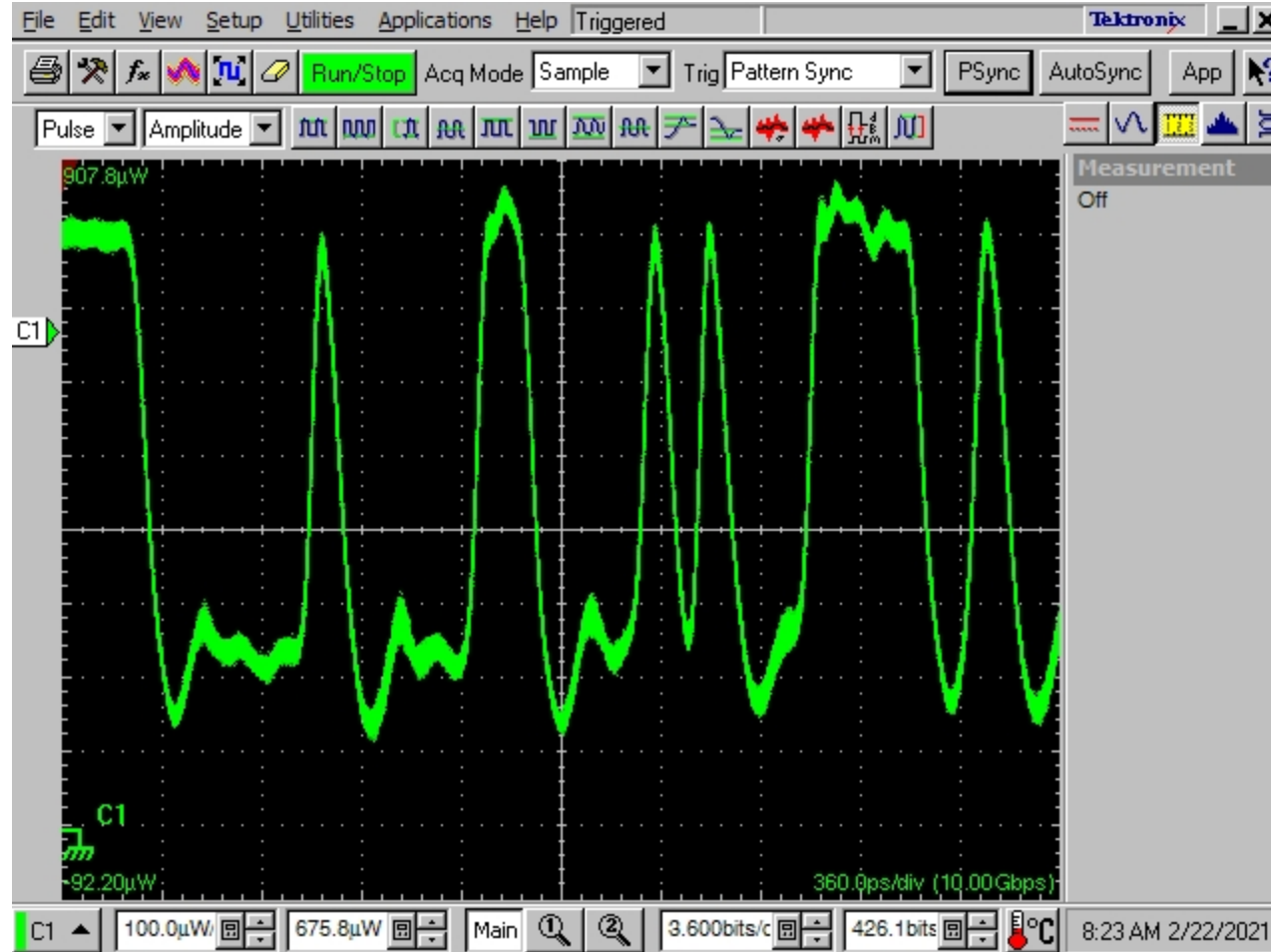
Measured Fall Time ($t_{meas}(\text{fall})$): 59 ps

Power Consumption: 204 mA @ 3.3 V

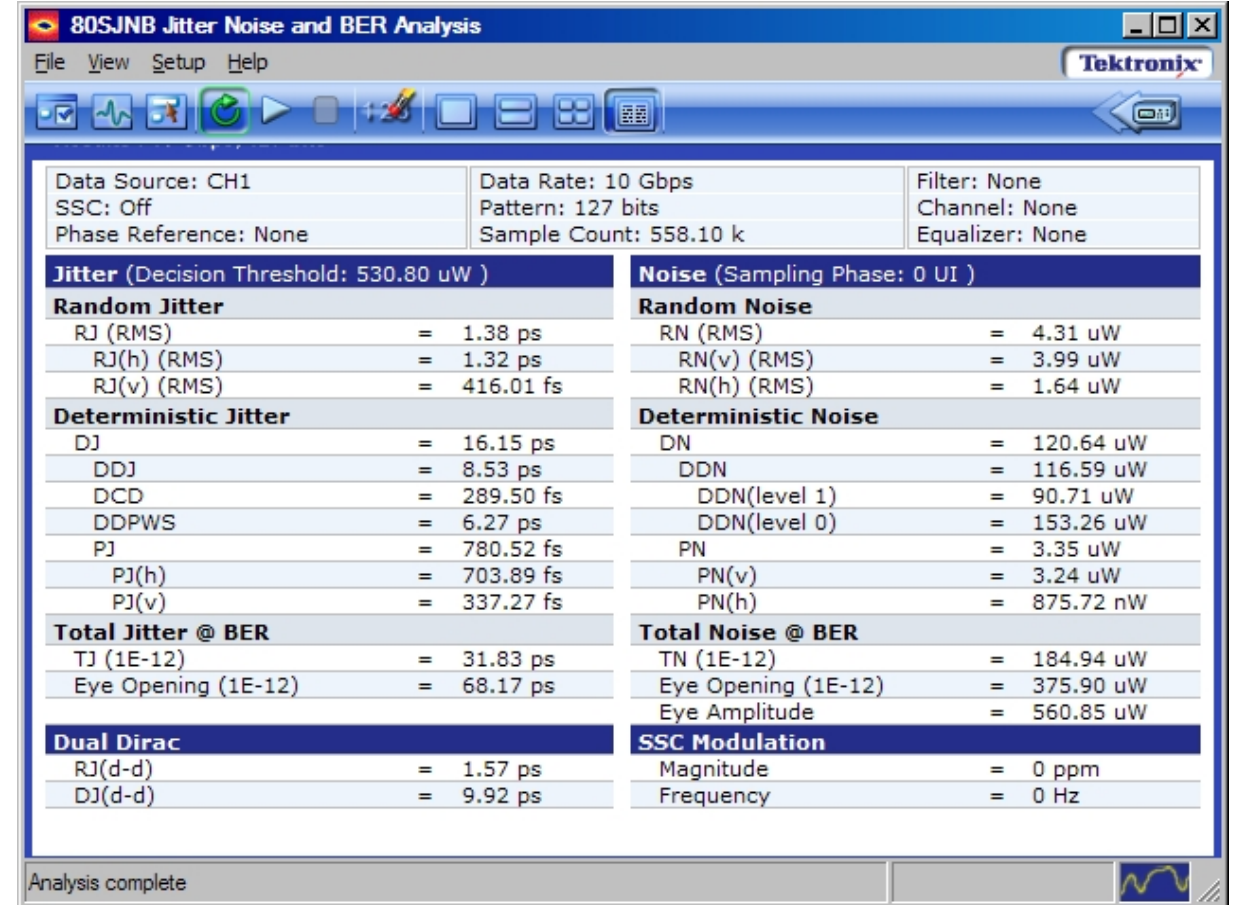
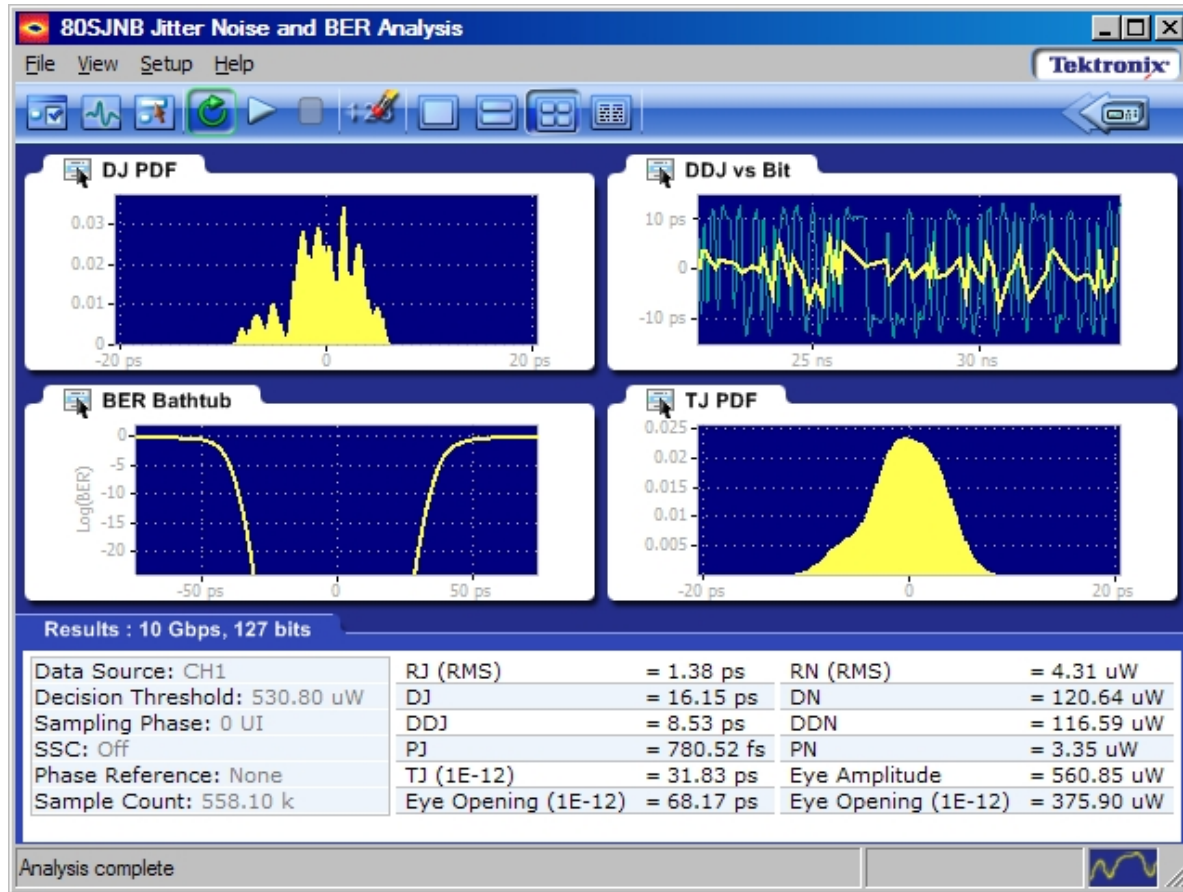
S/N F2020249554

Fabry-Perot (F-P) Device 1 Optical Pattern Sync Check 10 Gbps PRBS7 (127 bits)

This waveform is also viewed as a check that the instrument is synchronized with the repeating PRBS pattern (necessary for accurate jitter composition measurements)



Fabry-Perot (F-P) Device 1 Optical Jitter 10 Gbps PRBS7 (127 bits)



$$RJ_{\text{meas}} = 1.38 \text{ ps (RMS)}$$

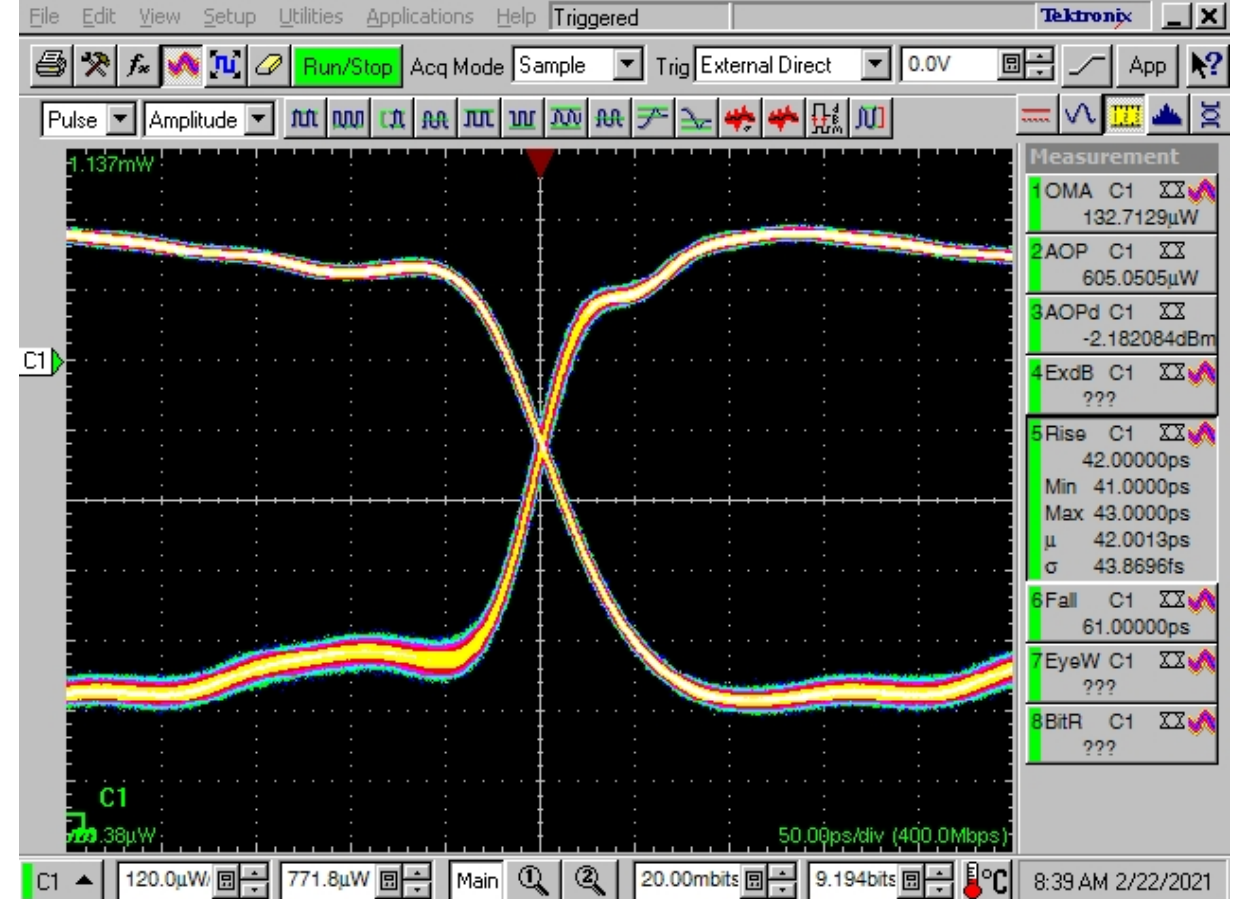
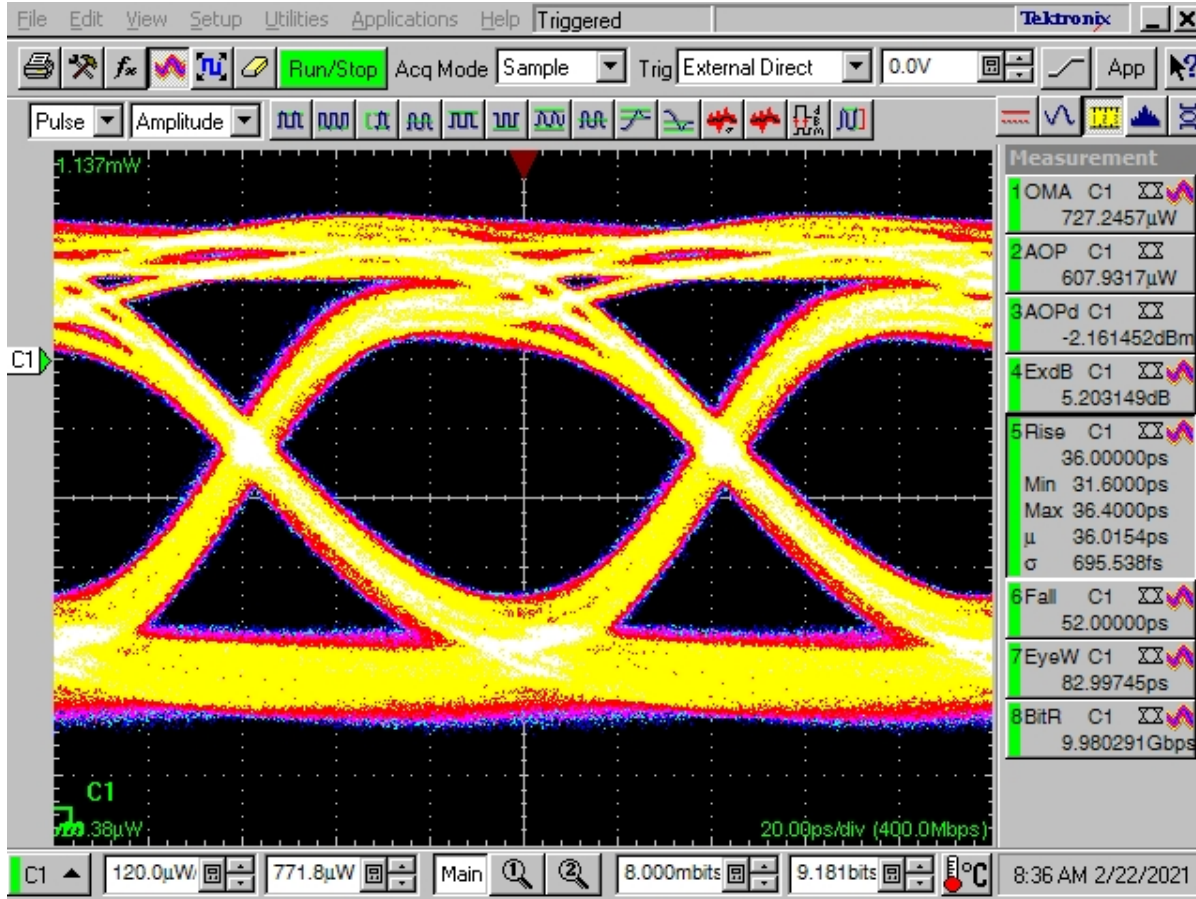
$$TJ_{\text{meas}} = 31.83 \text{ ps}$$

Distributed FeedBack (DFB) Device 1 Optical Eyes

10 Gbps PRBS7 (127 bits)

Average Optical Power: 607 μ W

Optical Modulation Amplitude: 727 μ W



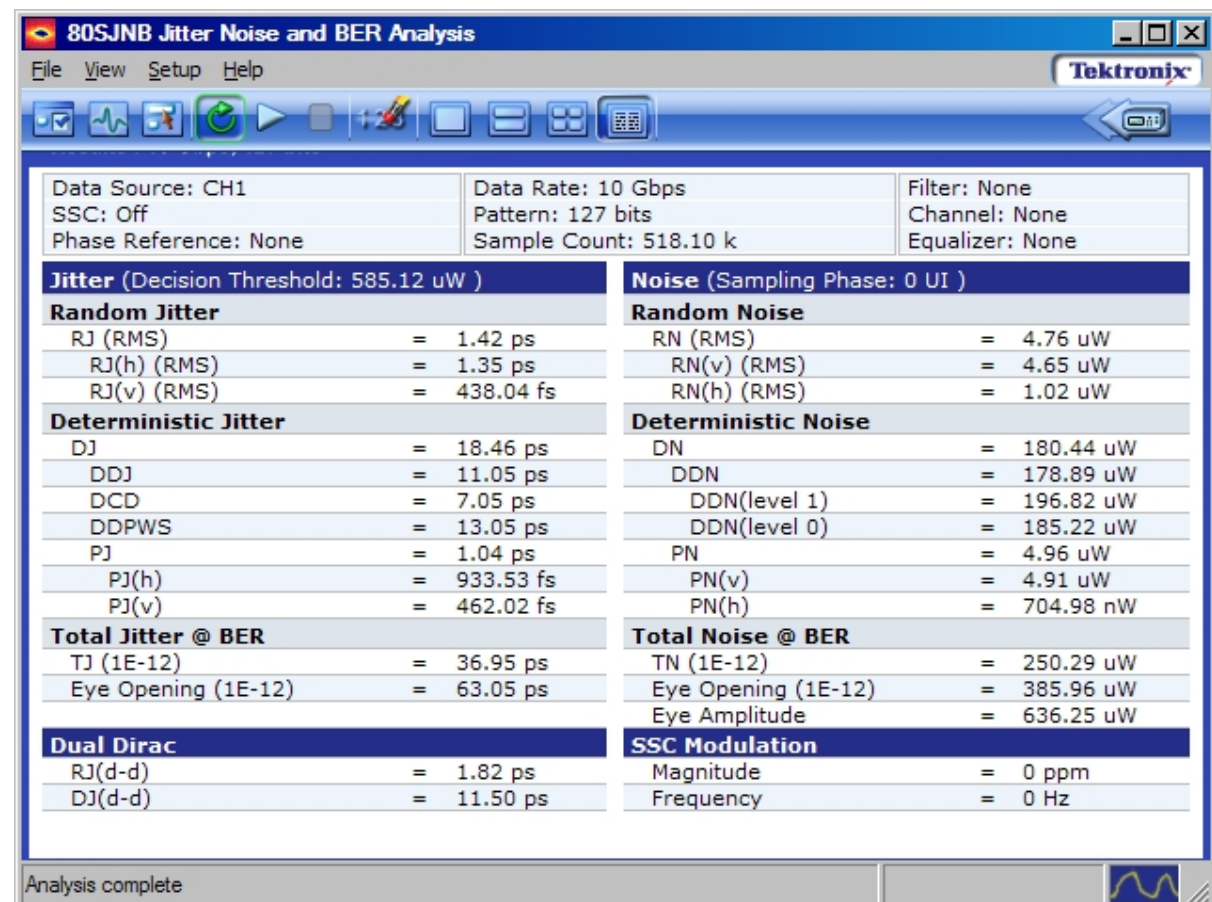
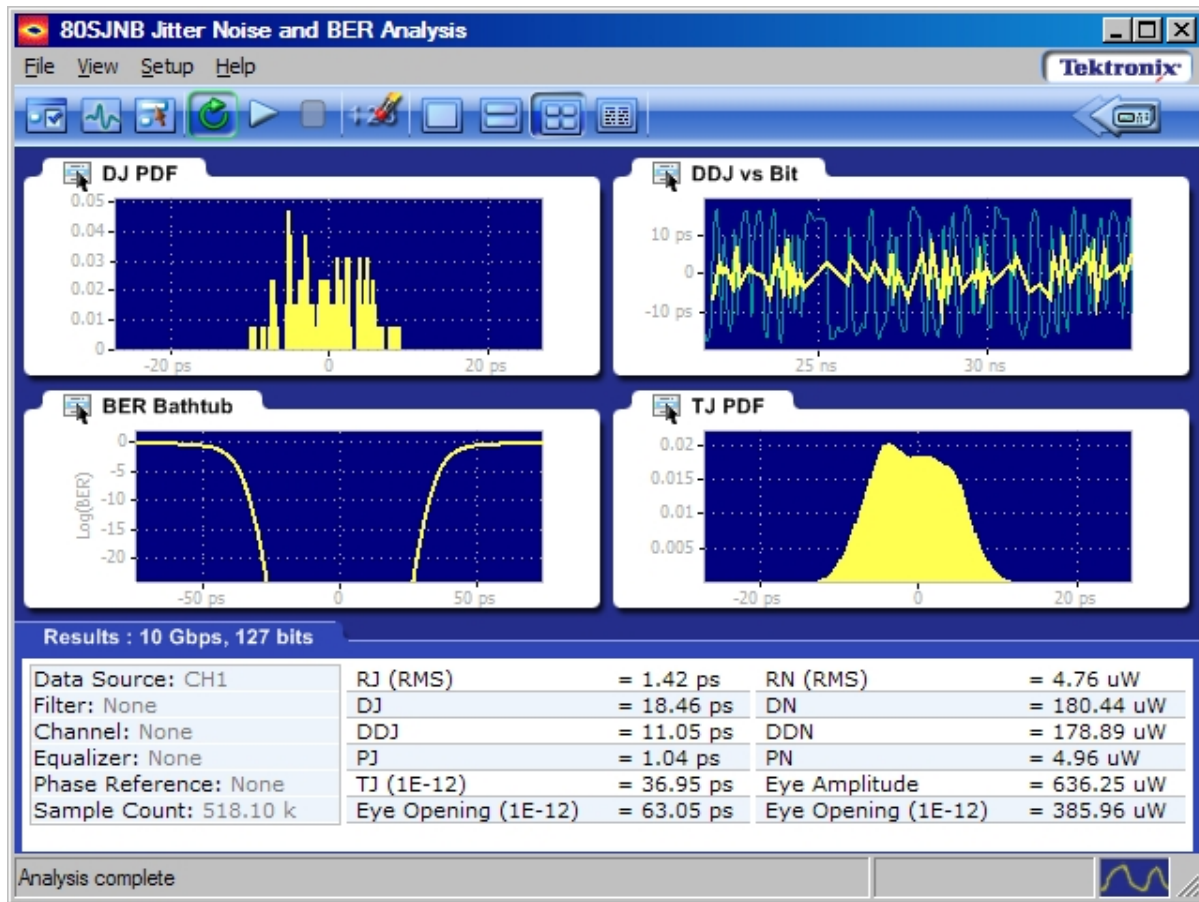
Extinction Ratio: 5.2 dB

Power Consumption: 239 mA @ 3.3 V

Measured Rise Time ($t_{\text{meas}}(\text{rise})$): 42 ps

Measured Fall Time: 61 ps

Distributed (DFB) Device 1 Optical Jitter 10 Gbps PRBS7 (127 bits)



$$RJ_{\text{meas}} = 1.42 \text{ ps (RMS)}$$

$$TJ_{\text{meas}} = 36.95 \text{ ps}$$

Next Steps

As of Feb. 23, a total of 7 such devices have been characterized. We have more on hand and will continue with measurements of this type at room temperature until we have approval for LiN₂ testing at the test stand.

We have obtained an optical spectrum analyzer so we will attempt to measure the spectra of the devices in order to make comparisons with LiN₂-tested devices.

A spreadsheet with the cumulative results of the testing will be maintained and all of the images from which the data have been drawn have been archived.

We are continuing to pursue the approvals for testing at the Feynman Computing Center.